

Notice of References Cited	Application/Control No. 10/014,610	Applicant(s)/Patent Under Reexamination AH SUE, JOHN DANY	
	Examiner Van Kim T. Nguyen	Art Unit 2661	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,693,911	02-2004	Yamanaka, Masayuki	370/395.3
	B	US-6,650,646	11-2003	Galway et al.	370/397
	C	US-6,636,484	10-2003	Agrawal et al.	370/248
	D	US-6,563,795	05-2003	Gruber et al.	370/248
	E	US-6,424,629	07-2002	Rubino et al.	370/241.1
	F	US-6,269,083	07-2001	Nagata et al.	370/248
	G	US-6,181,680	01-2001	Nagata et al.	370/248
	H	US-5,889,778	03-1999	Huscroft et al.	370/395.31
	I	US-5,878,031	03-1999	Ahmad et al.	370/249
	J	US-5,818,842	10-1998	Burwell et al.	370/397
	K	US-5,659,540	08-1997	Chen et al.	370/249
	L	US-2004/0052263	03-2004	Xu, Haibo	370/399
	M	US-2003/0210698	11-2003	Rouleau, Gordon	370/397

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.